


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/878,519	BEAN ET AL.	
	Examiner	Art Unit	
	Nhan T. Tran	2615	

SEARCHED			
Class	Subclass	Date	Examiner
348	231.\$.	5/9/2005	NT
348	157	5/11/2005	NT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	5/9/2005	NT